

MOS FIELD EFFECT TRANSISTOR μ PA1852

N-CHANNEL MOS FIELD EFFECT TRANSISTOR FOR SWITCHING

DESCRIPTION

The μ PA1852 is a switching device which can be driven directly by a 2.5-V power source.

The μ PA1852 features a low on-state resistance and excellent switching characteristics, and is suitable for applications such as power switch of portable machine and so on.

FEATURES

- Can be driven by a 2.5-V power source
- · Low on-state resistance

 $R_{DS(on)1} = 40 \text{ m}\Omega \text{ MAX.} \text{ (Vgs} = 4.5 \text{ V, Ip} = 3.0 \text{ A)}$

 $R_{DS(on)2} = 45 \text{ m}\Omega \text{ MAX.} \text{ (Vgs} = 4.0 \text{ V, Ip} = 3.0 \text{ A)}$

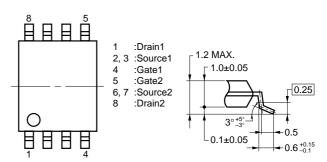
 $R_{DS(on)3} = 60 \text{ m}\Omega \text{ MAX.} \text{ (Vgs} = 2.5 \text{ V, Ip} = 3.0 \text{ A)}$

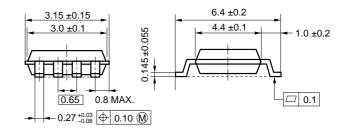
Built-in G-S protection diode against ESD

ORDERING INFORMATION

PART NUMBER	PACKAGE
μPA1852GR-9JG	Power TSSOP8

PACKAGE DRAWING (Unit : mm)





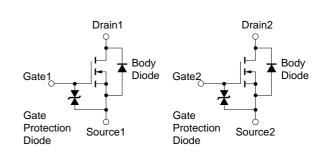
ABSOLUTE MAXIMUM RATINGS (TA = 25°C)

Drain to Source Voltage	Voss	20	V
Gate to Source Voltage	Vgss	±12	V
Drain Current (DC)	ID(DC)	±6.0	Α
Drain Current (pulse) Note1	D(pulse)	±24	Α
Total Power Dissipation Note2	PT	2.0	W
Channel Temperature	Tch	150	°C
Storage Temperature	T _{stg}	-55 to +150	°C

Notes 1. PW \leq 10 μ s, Duty Cycle \leq 1 %

2. Mounted on ceramic substrate of 5000 mm² x 1.1 mm

EQUIVALENT CIRCUIT



Remark The diode connected between the gate and source of the transistor serves as a protector against ESD. When this device actually used, an additional protection circuit is externally required if a voltage exceeding the rated voltage may be applied to this device.

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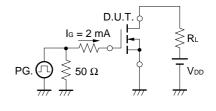
ELECTRICAL CHARACTERISTICS (TA = 25 °C)

CHARACTERISTICS	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT
Drain Cut-off Current	Ipss	Vps = 20 V, Vgs = 0 V			10	μΑ
Gate Leakage Current	lgss	V _{GS} = ±12 V, V _{DS} = 0 V			±10	μΑ
Gate Cut-off Voltage	V _{GS(off)}	V _{DS} = 10 V, I _D = 1 mA	0.5	0.74	1.5	V
Forward Transfer Admittance	yfs	Vps = 10 V, Ip = 3.0 A	1	10		S
Drain to Source On-state Resistance	RDS(on)1	Vgs = 4.5 V, Ib = 3.0 A		29	40	mΩ
	R _{DS(on)2}	V _G S = 4.0 V, I _D = 3.0 A		31	45	mΩ
	RDS(on)3	Vgs = 2.5 V, Ib = 3.0 A		39	60	mΩ
Input Capacitance	Ciss	Vps = 10 V		420		pF
Output Capacitance	Coss	V _G S = 0 V		265		pF
Reverse Transfer Capacitance	Crss	f = 1 MHz		120		pF
Turn-on Delay Time	td(on)	V _{DD} = 10 V		55		ns
Rise Time	tr	ID = 1.5 A		160		ns
Turn-off Delay Time	td(off)	V _{GS(on)} = 4.0 V		385		ns
Fall Time	tf	$R_G = 10 \Omega$		355		ns
Total Gate Charge	QG	V _{DD} = 10 V		6		nC
Gate to Source Charge	Qgs	ID = 6.0 A		2		nC
Gate to Drain Charge	Q _{GD}	Vgs = 4.0 V		3		nC
Diode Forward Voltage	VF(S-D)	IF = 6.0 A, Vgs = 0 V		0.74		V
Reverse Recovery Time	trr	IF = 6.0 A, VGS = 0 V		20		ns
Reverse Recovery Charge	Qn	di/dt = 15 A / μs		2		nC

TEST CIRCUIT 1 SWITCHING TIME

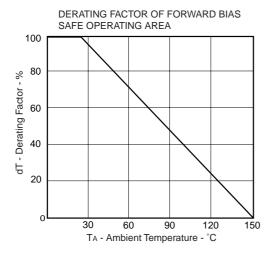
PG. $\bigcap_{RG} R_G = 10 \Omega$ $V_{GS} \bigvee_{Wave Form} V_{GS} \bigvee_{Wave Form} V_{G$

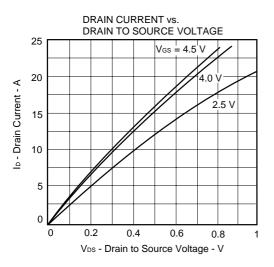
TEST CIRCUIT 2 GATE CHARGE

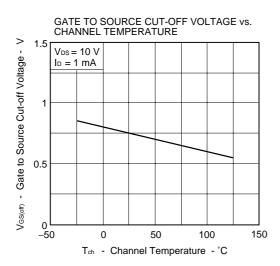


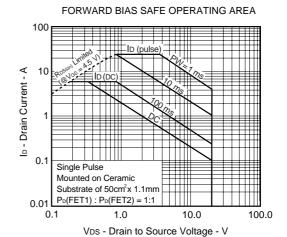


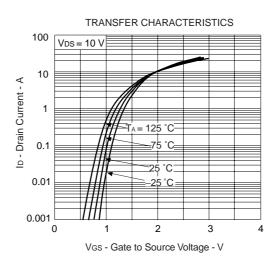
TYPICAL CHARACTERISTICS (TA = 25°C)

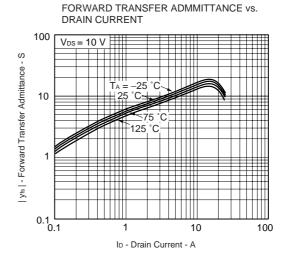






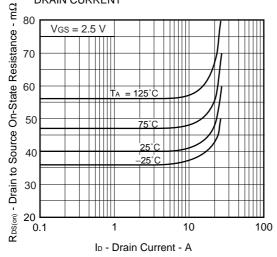




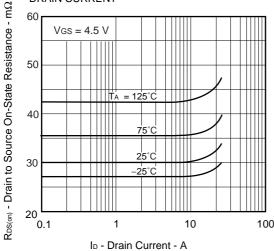


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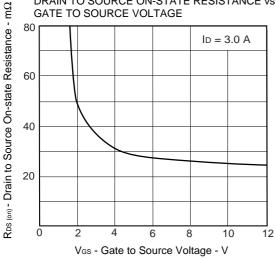
DRAIN TO SOURCE ON-STATE RESISTANCE vs. **DRAIN CURRENT**



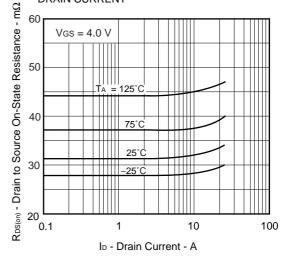
DRAIN TO SOURCE ON-STATE RESISTANCE vs. **DRAIN CURRENT**



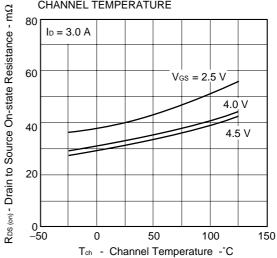
DRAIN TO SOURCE ON-STATE RESISTANCE vs.

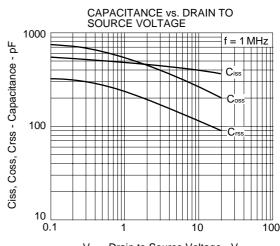


DRAIN TO SOURCE ON-STATE RESISTANCE vs. **DRAIN CURRENT**



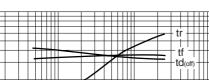
DRAIN TO SOURCE ON STATE RESISTANCE vs. CHANNEL TEMPERATURE





V_{DS} - Drain to Source Voltage - V

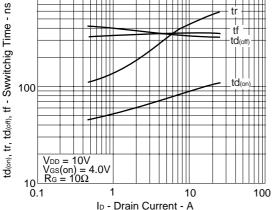
1000



10

100

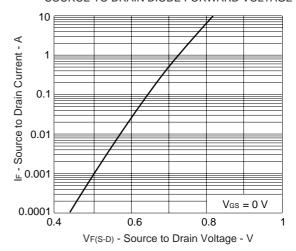
SWITCHING CHARACTERISTICS

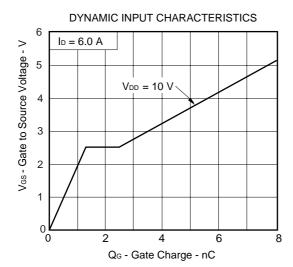


ID - Drain Current - A

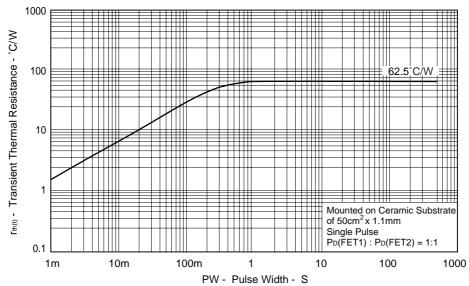
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SOURCE TO DRAIN DIODE FORWARD VOLTAGE





TRANSIENT THERMAL RESISTANCE vs. PULSE WIDTH



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NEC

 μ PA1852

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NEC μ PA1852

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